

# RDA012M4MS

12 Bit 1.3 GS/s Master-Slave 4:1 MUXDAC

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# 12 Bit 1.3 GS/s Master-Slave 4:1 MUXDAC

#### **Features**

- ♦ 12 Bit Resolution
- ♦ 1.3 GS/s Sampling Rate
- 4:1 Input Multiplexer
- Master-Slave Operation for Synchronous Operation of Multiple Devices
- ♦ Differential Analog Output
- ♦ Input Code Format: Offset Binary
- Output Swing: 600 mV with 50 Ω
   Termination
- ♦ 3.3V NMOS-Compatible Data Inputs
- ♦ Differential ECL or Sinusoidal Clock Input
- ♦ LVDS Compatible Clock Output
- ♦ 10 Bit Static Linearity
- Reference Output/Input Pin for Accurate Full-Scale Adjustment.
- ♦ 3.3V and -5.2V Power Supply
- ♦ 77 Lead HSD or 88 Lead QFP Package

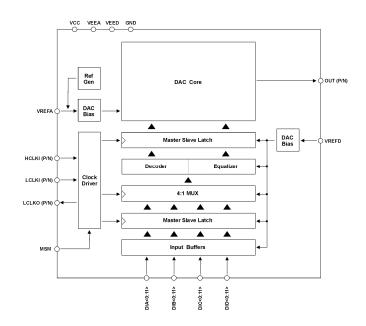


Figure 1 - Functional Block Diagram

## **Product Description**

The RDA012M4MS is a digital-to-analog converter (DAC) with a 4:1 input multiplexer and a maximum update rate of 1.3GS/s. The RDA012M4MS features master-slave operation that simplifies synchronization when multiple devices are required, such as in an I-Q modulation scheme. The integrated DAC utilizes a segmented current source to reduce the glitch

energy and achieve high linearity performance. For best dynamic performance, the DAC outputs are internally terminated with  $50\Omega$  resistance, and outputs a nominal full-scale current of 12mA when terminated with external  $50\Omega$  resistors. For a convenient interface with most CMOS ICs, the digital data inputs are low voltage NMOS compatible.

## Ordering information

PART NUMBER	DESCRIPTION		
RDA012M4MS-DI	12 BIT 4:1 MUX 1.3GS/s DAC, DIE		
RDA012M4MS-HD	12 BIT 4:1 MUX 1.3GS/s DAC, 77 Lead HSD Package	CAUTION  DEVICE SUSCEPTIBLE TO	
RDA012M4MS-QP	12 BIT 4:1 MUX 1.3GS/s DAC, 88 Lead QFP Package	DEVICE SUSCEPTIBLE TO DAMAGE BY ELECTROSTATIC DISCHARGE (ESD)	
EVRDA012M4MS-HD   RDA012M4MS-HD Evaluation Board			
EVRDA012M4MS-QP	RDA012M4MS-QP Evaluation Board		



# Absolute Maximum Ratings

Supply Voltages           Between GNDs         -0.3V to +0.3V           Between VCCs         -0.3V to +0.3V           VCCs to GND         0V to +3.8V
RF Input Voltages CLKIP, CLKIN to GND3 V to 1 V
HS Digital Input Voltages DI<0:11>0V to VCC
Output Termination Voltages OUTP, OUTN to GND1 V to 1 V
Temperature         Case Temperature       -40 to +85 °C         Junction Temperature       +125 °C         Lead, Soldering (10 Seconds)       +220 °C         Storage       -60 to 125 °C



# **DC Electrical Specification**

Test Conditions (see notes for specific conditions): Room Temperature; VCC = 3.3V; VEEA = -5.2V; VEED = -5.2V; VREFA = -2V; VREFD = -2V; Clock: 1.3GHz, 0.6Vpp Differential; Outputs Terminated Into 50  $\Omega$  to 0V.

	PARAMETER	SYMBOL	CONDITIONS, NOTE	MIN	TYP	MAX	UNITS		
1.0	DC TRANSFER FUNCTION								
1.1	Differential Nonlinearity	DNL	Maximum of Absolute Value		4		LSB		
1.2	Integral Nonlinearity	INL	Maximum of Absolute Value		4		LSB		
2.0	TEMPERATURE DRIFT								
2.1	Warm-up Time		After Power-up			30	S		
3.0	HIGH CLOCK INPUT (HCL	KIP, HCLK	IN)						
3.1	Input Resistance	R <sub>CIN</sub>	Resistance to VTT	45	50	55	Ω		
4.0	DIGITAL INPUTS (DIA<0:1	1>, DIB<0:	11>, DIC<0:11>, DID<0:11>)						
4.1	Input Resistance	$R_{DIN}$			2K		Ω		
5.0	LOW CLOCK INPUT (LCL	(IP, LCLKI	N)						
5.1	Input Resistance	R <sub>LCIN</sub>	Differential LVDS		100		Ω		
6.0	LOW CLOCK OUTPUT (LC	LKOP, LC	LKON)	•	•				
6.1	Common Mode	$V_{CM,LCKO}$		0.9	1.2	1.5	V		
6.2	Amplitude Voltage	$V_{CPP,LCKO}$	Differential LVDS	250	350	450	mV		
7.0	ANALOG OUTPUTS (OUTP	P, OUTN)		•					
7.1	Full-scale Output Swing	V <sub>FSD</sub>	Differential, Terminated Into 50Ω to GND on Each Output	1140	1200	1260	mVpp		
7.2	Full-scale Output Swing	V <sub>FSS</sub>	Single Ended, Terminated Into $50\Omega$ to GND	570	600	630	mVpp		
7.3	Full-scale Output Range	V <sub>FSRS</sub>	Single Ended, Terminated Into 50Ω to GND (MIN=000h, MAX=FFFh)	-650		0	V		
7.4	Output Current	I <sub>OUT</sub>	Terminated Into 50Ω to GND		12		mΑ		
8.0	ANALOG REFERENCE (VF	REFA)		•	•				
8.1	Reference Voltage	$V_{VREFA}$	Output from Internal Reference	-1.9	-2	-2.1	V		
9.0	DIGITAL REFERENCE (VR								
9.1	Reference Voltage	$V_{VREFD}$	Output from Internal Reference	-1.9	-2	-2.1	٧		
10.0	POWER SUPPLY REQUIRE	EMENTS							
10.1	Positive Current	ICC			150		mΑ		
10.2	Negative Current, Analog	IEEA			95		mA		
10.3	Negative Current, Digital	IEED			420		mA		
10.4	Power Dissipation	Р	Total Dissipation		3.3		W		
10.5	Power Dissipation	P <sub>VCC</sub>	Positive Supply		0.5		W		
10.6	Power Dissipation	$P_{VEEA}$	Negative Supply, Analog		0.5		W		
10.7	Power Dissipation	P <sub>VEED</sub>	Negative Supply, Digital		2.3		W		



## AC Electrical Specification

Test Conditions (see notes for specific conditions): Room Temperature; VCC = 3.3V; VEEA = -5.2V; VREFA = -2V; VREFD = -2V; Clock: 1.3GHz, 0.6Vpp Differential; Outputs Terminated Into 50  $\Omega$  to 0V.

	PARAMETER	SYMBOL	CONDITIONS, NOTE	MIN	TYP	MAX	UNITS
11.0	DYNAMIC PERFORMANCE						
11.1	SFDR	SFDR 1	$F_{CLK} = 800MHz$ , $F_{OUT} = 267MHz$		56		dBc
11.2	SFDR	SFDR 2	$F_{CLK} = 1GHz, F_{OUT} = 333MHz$		53		dBc
11.3	SFDR	SFDR 3	$F_{CLK} = 1.3GHz, F_{OUT} = 400MHz$		50		dBc
12.0	DATA TIMING (DIA<0:11>, DIB<0:11>, DIC<0:11>, DID<0:11>)						
12.1	Data In to LCLKO Setup	t <sub>DTLCKST</sub>		300			ps
12.2	Data In to LCLKO Hold	t <sub>DTLCKHD</sub>		-50			ps

## **Operating Conditions**

	PARAMETER	SYMBOL	CONDITIONS, NOTE	MIN	TYP	MAX	UNITS	
13.0	HIGH CLOCK INPUT (HCLKIP, HCLKIN)							
13.1	Amplitude	$V_{CPP}$	Differential ECL	400	600	800	mV	
13.2	Common Mode Voltage	$V_{CCM}$		-0.8	-1.5	-2	V	
13.3	Maximum Frequency	F <sub>MAX</sub>		1300			MHz	
13.4	Minimum Frequency	F <sub>MIN</sub>				1	MHz	
14.0	LOW CLOCK INPUT (LCLKIP	, LCLKIN)						
14.1	Amplitude	$V_{LCPP}$	Differential LVDS	250	350	450	mV	
14.2	Common Mode Voltage	$V_{LCCM}$		0.9	1.2	1.5	٧	
15.0	DIGITAL INPUTS (DIA<0:11>	, DIB<0:11	>, DIC<0:11>, DID<0:11>)					
15.1	Input High Voltage	$V_{IH}$		0.9		VCC	V	
15.2	Input Low Voltage	$V_{IL}$		-0.4		0.4	V	
16.0	TERMINATION VOLTAGE (V	TT)						
16.1	Termination Voltage	$V_{TT}$	Termination Voltage for HCLKI		-2		V	
17.0	ANALOG REFERENCE (VRE	FA) <sup>1</sup> (note	1)					
17.1	Reference Voltage	$V_{REF}$		-2.5	-2	-1.2	V	
18.0	DIGITAL REFERENCE (VREF	·D)						
18.1	Reference Voltage	$V_{REF}$		-2.5	-2	-1.2	V	
19.0	POWER SUPPLY REQUIREM	IENTS						
19.1	Positive Supply Voltage	VCC		3.1	3.3	3.5	V	
19.2	Analog Supply Voltage	VEEA		-5.4	-5.2	-5.0	V	
19.3	Digital Supply Voltage	VEED		-5.4	-5.2	-5.0	V	
20.0	OPERATING TEMPERATURE <sup>2</sup> (note 2)							
20.1	Case Temperature	Tc	Measured at Bottom Plate	-40		85	å	
20.2	Junction Temperature	Tj				125	Ŝ	

The DAC core current is generated from an internal reference that is both temperature and supply dependent. The Internal reference can change up to ±2% by changing the supply voltage within the specified range. It can also change up to ±5% according to operating temperature changes. The change in temperature and supply can be minimized by using a precision external voltage reference source connected to VREFA.

The part is designed to function with a junction temperature up to 125°C. For the best performance, operation within the specified temperature range with a proper heatsink attached to the device is recommended. The heatsink should be attached to the bottom of the PCB, on a metal pad connect by thermal vias to the metal pad where the part is soldered.



## Pin Description and Pin Layout (HSD Package)

P/I/O	PIN	NUM.	NAME	FUNCTION	
Р	7, 14, 39, 62	4	VCC	+3.3V Digital Power Supply	
Р	68, 71, 72, 73, 74, 75, 76	7	VEEA	-5.2V Analog Power Supply	
Р	8, 12, 26, 52, 64, 67	6	VEED	-5.2V Digital Power Supply	
Р	Bottom Plate	-	GND	Ground	
I	77	1	VREFA	-2V Reference Voltage	
- 1	10	1	VREFD	Digital Circuitry Bias Reference. Bypass to Ground	
I	4	1	VTT	HCLKI Clock Termination Voltage	
I	6	1	MSM	Master-Slave Mode Selection: Float - Master GND - Slave	
ı	5	1	HCLKIP	Clock Input	
I	3	1	HCLKIN	Clock Iliput	
I	24	1	LCLKIP	Low Clock Input	
	25	1	LCLKIN	Low Glock Input	
I	2	1	LCLKOP	Low Clock Output	
ı	1	1	LCLKON	Low Glock Gulpul	
I	9, 16, 20, 27, 31, 35, 40, 44, 48, 53, 57, 61	12	DIA<0:11>	DIA <i> Is Channel A Digital Bit i Input. MSB is bit 11</i>	
I	11, 17, 21, 28, 32, 36, 41, 45, 49, 54, 58, 63	12	DIB<0:11>	DIB <i> Is Channel B Digital Bit i Input. MSB is bit 11</i>	
I	13, 18, 22, 29, 33, 37, 42, 46, 50, 55, 59, 65	12	DIC<0:11>	DIC <i> Is Channel C Digital Bit i Input. MSB is bit 11</i>	
I	15, 19, 23, 30, 34, 38, 43, 47, 51, 56, 60, 66	12	DID<0:11>	DID <i> Is Channel D Digital Bit i Input. MSB is bit 11</i>	
0	70	1	OUTP	Differential Output	
0	69	1	OUTN	Dinordina Guipui	

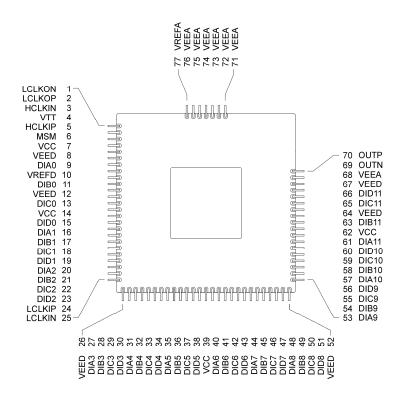


Figure 2 - RDA012M4MS-HD pinout (top view).



## Pin Description and Pin Layout (QFP Package)

P/I/O	PIN	NUM.	NAME	FUNCTION
Р	41, 62	2	VCC	+3.3V Digital Power Supply
Р	2, 3, 6, 7, 8, 9	6	VEEA	-5.2V Analog Power Supply
Р	43, 44, 59, 60	4	VEED	-5.2V Digital Power Supply
Р	1, 4, 5, 10, 12, 15, 42, 61, 63, 80, 81, 82, 84, 86, 87, 88	16	GND	Ground
Р	Bottom Plate	-	GND	Ground
ı	11	1	VREFA	-2V Reference Voltage
I	20	1	VREFD	Digital Circuitry Bias Reference. Bypass to Ground
ı	17	1	VTT	HCLKI Clock Termination Voltage
I	19	1	MSM	Master-Slave Mode Selection: Float - Master GND - Slave
ı	18	1	HCLKIP	Clock Input
ı	16	1	HCLKIN	Clock Input
I	45	1	LCLKIP	Low Clock Input
ı	46	1	LCLKIN	Low Glock Input
I	14	1	LCLKOP	Low Clock Output
ı	13	1	LCLKON	Low Glock Output
ı	21, 25, 29, 33, 37, 47, 51, 55, 64, 68, 72, 76	12	DIA<0:11>	DIA <i> Is Channel A Digital Bit i Input. MSB is bit 11</i>
ı	22, 26, 30, 34, 38, 48, 52, 56, 65, 69, 73, 77	12	DIB<0:11>	DIB <i> Is Channel B Digital Bit i Input. MSB is bit 11</i>
I	23, 27, 31, 35, 39, 49, 53, 57, 66, 70, 74, 78	12	DIC<0:11>	DIC <i> Is Channel C Digital Bit i Input. MSB is bit 11</i>
I	24, 28, 32, 36, 40, 50, 54, 58, 67, 71, 75, 79	12	DID<0:11>	DID <i> Is Channel D Digital Bit i Input. MSB is bit 11</i>
0	85	1	OUTP	Differential Output
0	83	1	OUTN	Dinordinal Odiput

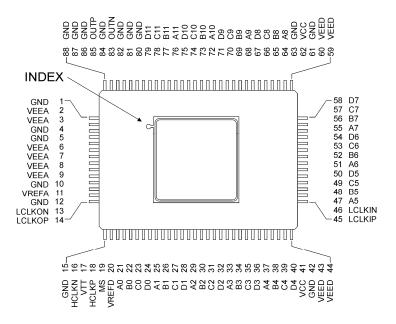


Figure 3 - RDA012M4MS-QP pinout (top view).



## Pad Layout

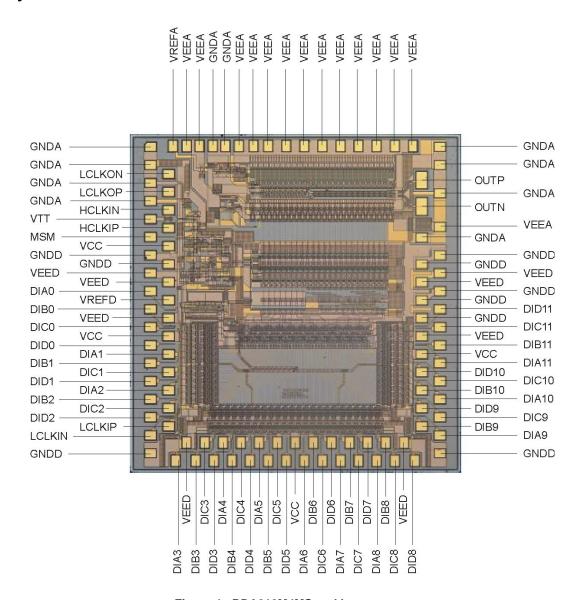


Figure 4 - RDA012M4MS pad layout.



### Theory of Operation

For best dynamic and static performance, the DAC employs 6-bit segmentation. The 3.3V NMOS compatible 12-bit digital data inputs are latched by a master-slave flip-flop immediately after the input buffer to reduce the data skew. The four-channel data are combined together by the 48:12 MUX and latched again. The 6 MSB data bits are decoded into thermometer code by a two-stage decoding block, and the 6 LSB data bits are transported through the delay equalizer block. The digital data are synchronized again by a second master slave flip-flop to reduce the switching glitch. The decoded 6 MSB data drive 63 identical current switches, and the 6 LSB data drive 6 current switches. The output nodes from the LSB current switches are connected to the analog output through an R-2R ladder to generate the binary output.

The DAC output full-scale voltage follows the relationship  $V_{FS} = 0.3 \text{xV}_{REF.}$  An internal reference circuit with approximately -10dB supply rejection is integrated on chip for application convenience. The reference pin is provided for monitoring and for bypass purposes. To band-limit the noise on the reference voltage, the reference pin should be bypassed to the GNDA node with capacitance > 100pF. The VREF pin can also be used to override the internal reference with an accurate,

temperature-compensated external voltage reference.

The timing diagram is shown in Figure 5. The 1.3GHz external clock (HCLK) is divided by 2 and 4 resulting in the MUX internal selection signals S0 and S1. A low-speed clock (LCLK) is provided to drive the external digital. The four-channel data input are latched with an internal clock that is synchronized with the LCLK. Controlled by S0 and S1, input data are fed to the 1.3GS/s DAC in the order shown.

For applications requiring two MUXDACs, such as quadrature modulation, the RDA012M4MS offers master and slave mode operation. This provides synchronization between the two MUXDACs in a straightforward manner. Figure 7 illustrates two MUXDACs in an I-Q configuration and 1 GS/s conversion rate. The I-MUXDAC is in master mode and the Q-MUXDAC is in slave mode. The master MUXDAC generates an LVDS compatible 250MHz clock signal that is input to the slave MUXDAC where it is used to synchronize the generation of the select signal for the input muxes. The slave device then feeds this clock to the FPGA clock driver. For proper synchronization, the delay associated with the LVDS clock signal from master to slave MUXDAC must not exceed one clock period of the high-speed clock.

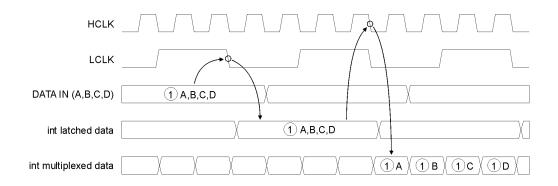


Figure 5 - Input Timing Diagram.



### Signal Description

#### HIGH SPEED INPUT CLOCK.

The RDA012M4MS high-speed clock input is differential and can be driven from typical ECL circuits. Also a differential sinusoidal clock can be used. The HCLKIP and HCLKIN inputs, are internally terminated with 50  $\Omega$  to VTT which should be connected to a well decoupled -2.0 volt supply. Since the MUXDAC's output phase noise is directly related to the input clock noise and jitter, a low-jitter clock source is ideal. The internal clock driver generates very little added jitter (~100fs). A 500MHz MUXDAC output demands a white noise induced clock jitter of less than 250fs for a 10-bit equivalent, 62dB SNDR.

#### DATA INPUT.

The data inputs are 3.3V NMOS-compatible. The data is interleaved according to significant bit. For example, consecutive data pins will occur as A0, B0, C0, D0, A1, B1, etc.

#### **OUTPUT CLOCK.**

Output clock LCLKOP and LCLKON are supplied for the DSP/FPGA/ASIC in slave mode, or connected to another MUXDAC if in master mode. They are LVDS compliant and needs to be terminated with a100 $\Omega$  resistor in front of the clock driver for the ASIC/DSP.

For application convenience, the data input's setup and hold time is specified with respect to the LCLKO. It should be noted that LCLKOP and LCLKON are driven by the MUXDAC and the waveforms of these signals are better defined at the receiver end; that is, near the ASIC/DSP chip that provides the input data for the MUXDAC. The system designer should consider the delay associated with the signal routing in the system's timing budget.

The setup and hold time of the LCLK to data transition are defined at the MUXDAC side. Data transitions of the data input have to occur during the "Valid Data Transition Window." The timing margin seen from the MUXDAC is  $T_P$ - $T_S$  where  $T_P$  is the LCLKO period and  $T_S$  is the setup time, assuming that the ASIC chip takes LCLKO as the clock input and its outputs are latched at the

falling edge of the clock. From the ASIC/DSP end, however, the timing margin is decreased by the amount equal to the sum of the data delay and clock delay between the two chips.

#### ANALOG OUTPUT.

The outputs DACOUTP and DACOUTN should both be connected though a 50  $\Omega$  resistor to ground. This will give a full-scale amplitude of 0.6 volt (both outputs must be terminated), 1.2 volt differentially. The output common mode can be changed by terminating the load resistors to a different voltage. The device is optimized to perform best when connected to a voltage between 0 and 1 volt, however. For reliable operation, the output termination voltage should not exceed 3 volts.

#### REFERENCE.

VREFA is provided for added control of the fullscale amplitude output. The internal reference circuit is designed to provide -2.0 volts, which can change up to ±5% as the supply voltage and/or operating temperature changes. If the user prefers accurate absolute full-scale, use an external voltage reference with low output impedance to override the internal reference. The output full-scale voltage follows the relationship  $V_{FS} = 0.3xV_{REF}$ . Note that the MUXDAC is optimized to have the best performance with a reference voltage of -2.0 volts. The output resistance of the reference node is 560  $\Omega$  ±10%. VREFD allows adjusting of the digital circuitry bias point for varying input voltage swings. In most cases, VREFD should be bypassed to GND.



# **Typical Operating Circuit**

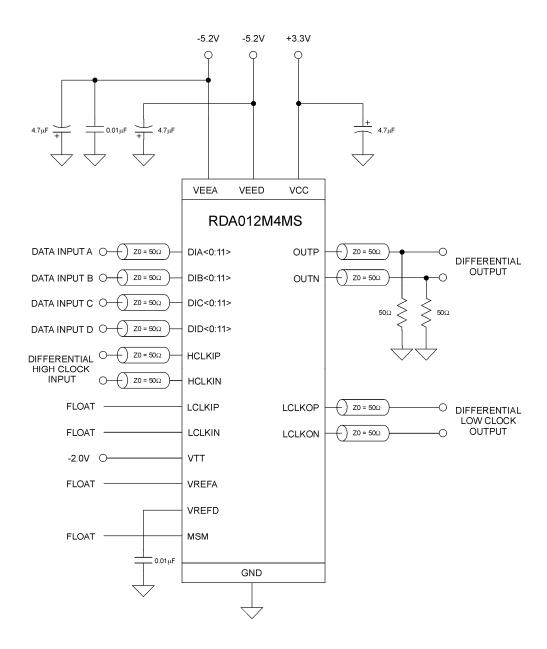


Figure 6 - RDA012M4MS typical operating circuit using the internal voltage reference.



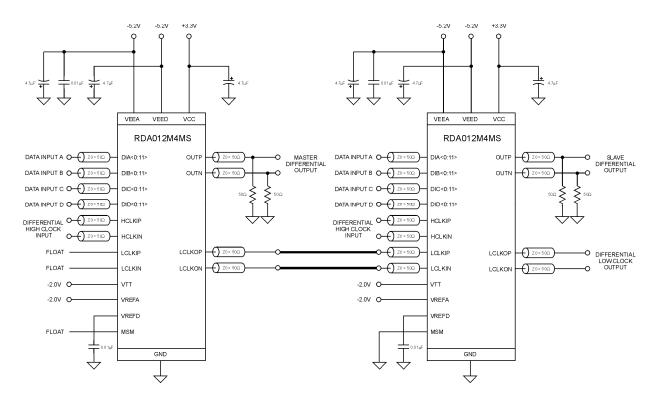


Figure 7 - RDA012M4MS typical operating circuit in master-slave mode using external voltage reference.

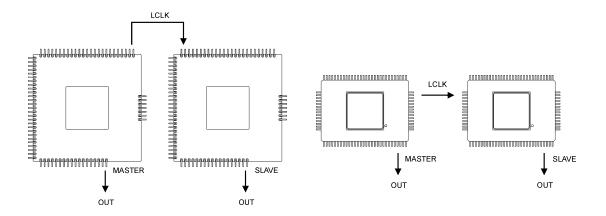


Figure 8 - RDA012M4MS recommended placement in master-slave mode to minimize LCLK routing.



# **Typical Performance**

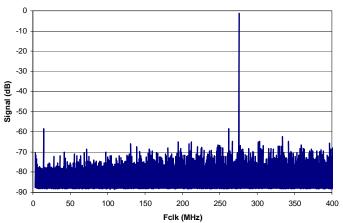


Figure 9 - Output spectrum at Fclk=800MHz, Fout=270MHz

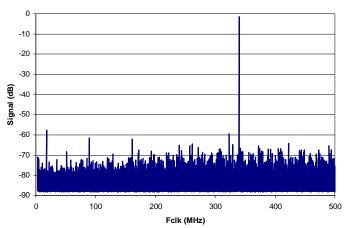


Figure 10 - Output spectrum at Fclk=1000MHz, Fout=340MHz

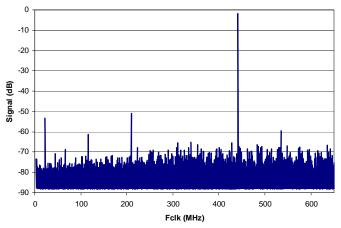


Figure 11 - Output spectrum at Fclk=1300MHz, Fout=440MHz



# Package Information - 77 Lead HSD

There is a heat sink slug on the package's bottom. The leads are gull-winged formed and trimmed to 0.053 inch (1.35 mm) in length.

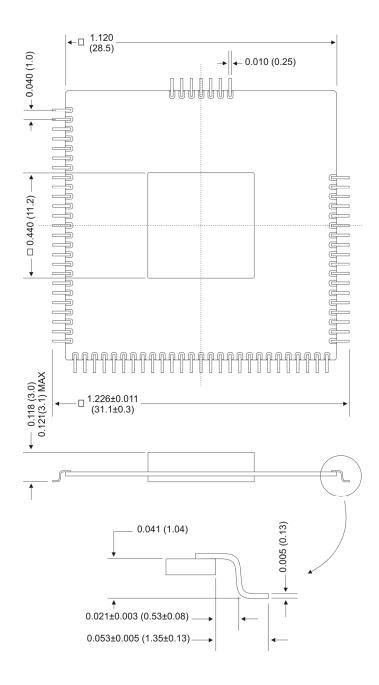


Figure 12 - RDA012M4MS-HD package, dimensions shown in inches (mm).



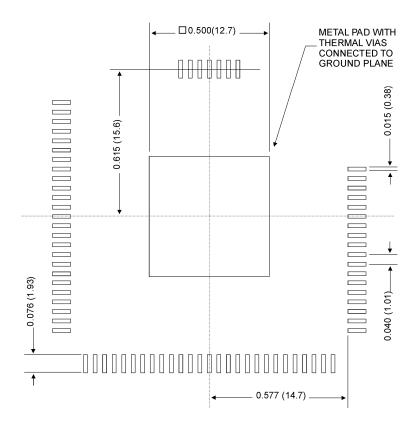


Figure 13 - RDA012M4MS-HD footprint, dimensions shown in inches (mm).



# Package Information - 88 Lead QFP

There is a heatsink slug on the package's bottom. The thermal resistance from junction to case (at the heatsink) is approximately 3.5 C/W.

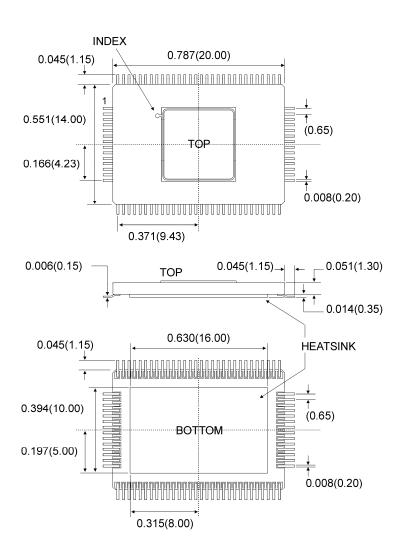


Figure 14 - RDA012M4MS-QP package, dimensions shown in inches (mm).



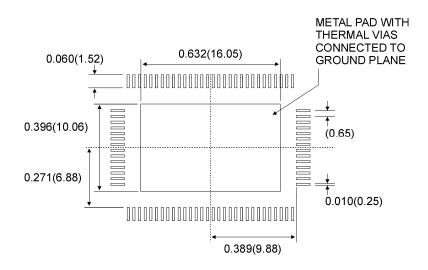


Figure 15 - RDA012M4MS-QP footprint, dimensions shown in inches (mm).